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PATENT
ABM (JW)
105 (JW)



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

RECEIVED

Sharad Kapur, et al. APR 03 2003
Serial No.: 09/427,238 Technology Center 2100
Filed: October 26, 1999
For: SYSTEM AND METHOD FOR DETERMINING CAPACITANCE
FOR LARGE-SCALE INTEGRATED CIRCUITS RECEIVED
Group No.: 2123 APR 03 2003
Examiner: Eduardo Garcia-Otero Technology Center 2100

Commissioner for Patents
Washington, D. C. 20231

Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on 03/21/2003 (Date).
Stephanie Pitt
(Printed or typed name of person signing the certificate)
Signature of Pitt
(Signature of the person signing the certificate)

"REQUEST FOR APPROVAL OF PROPOSED DRAWING CORRECTION"

FIGURES 1 and 2B have been modified to provide a better understanding of the subject matter. Since these aspects of the present invention were submitted in the application as originally filed, the corrected drawings do not constitute new matter. The Applicants hereby submit a proposed drawing correction for the appropriate figures in which the proposed corrections are marked in red ink. Accordingly, approval of each of the proposed drawing corrections is respectfully requested.

In the event that each proposed drawing correction is not approved in its entirety, the undersigned will attend to the correction of these drawings in the manner specified by the Examiner.

Respectfully submitted,

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Date: 3/27/03

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